
Space systems — General test methods for spacecraft, subsystems and units

*Systèmes spatiaux — Méthodes d'essai générales pour véhicules
spatiaux, sous-systèmes et équipements*



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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by Technical Committee ISO/TC 20, *Aircraft and space vehicles*, Subcommittee SC 14, *Space systems and operations*.

This second edition cancels and replaces the first edition (ISO 15864:2004), which has been technically revised.

The main changes compared to the previous edition are as follows:

- harmonized expressions throughout this document, including terminologies;
- added necessary but minimum modifications to requirements such as traceability in [4.9.6](#) and magnetic test in [7.4](#);
- added the most current published documents as normative references: ISO 19924 and ISO 21494.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Throughout this document, the minimum essential criteria are identified by the use of the keyword “shall”. Recommended criteria are identified by the use of the keyword “should” and, while not mandatory, are considered to be of primary importance in providing serviceable, economical and practical designs. Deviations from the recommended criteria should occur only after careful consideration, extensive testing and thorough service evaluation have shown alternative methods to be satisfactory. The acceptance criteria, specifications or procedures, and other detail test requirements applicable to a particular programme are defined in the applicable technical specifications and statement of work. When requirements have to be verified by measuring product performance and function under various simulated environments, the method is referred to as “Test”. The requirements of this document may be tailored for each specific space programme application.